

<b>Notice of References Cited</b>	Application/Control No. 10/522,980		Applicant(s)/Patent Under Reexamination SUDO, HIROAKI	
	Examiner Pablo N. Tran		Art Unit 2618	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0208258	10-2004	Lozano et al.	375/295
*	B	US-7,113,558	09-2006	Lozano et al.	375/347
*	C	US-7,050,510	05-2006	Foschini et al.	375/299
*	D	US-7,027,523	04-2006	Jalali et al.	375/296
*	E	US-6,987,819	01-2006	Thomas et al.	375/342
*	F	US-2006/0291581	12-2006	Onggosanusi et al.	375/267
*	G	US-2006/0285585	12-2006	Sampath, Hemanth	375/227
*	H	US-2006/0250941	11-2006	Onggosanusi et al.	370/208
*	I	US-2006/0189280	08-2006	Goldberg, Steven J.	455/101
*	J	US-2006/0159160	07-2006	Kim et al.	375/148
*	K	US-2006/0083291	04-2006	Hongming et al.	375/148
*	L	US-2005/0265465	12-2005	Hosur et al.	375/260
*	M	US-2005/0063345	03-2005	Wu et al.	370/335

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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